TK3A65DA



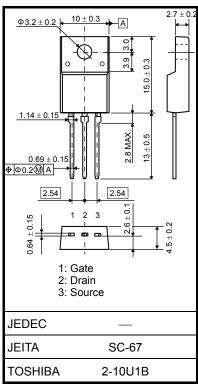
Unit: mm

Switching Regulator Applications

- Low drain-source ON-resistance: RDS (ON) = 2.3 Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 2.2 \text{ S (typ.)}$
- Low leakage current: $I_{DSS} = 10 \mu A \text{ (max) (V}_{DS} = 650 \text{ V)}$
- Enhancement mode: $V_{th} = 2.4 \text{ to } 4.4 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA)}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	650	V	
Gate-source voltage		V _{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	2.5		
	Pulse (t = 1 ms) (Note 1)	I _{DP}	10	Α	
Drain power dissipati	on (Tc = 25°C)	P _D	35	W	
Single pulse avalanche energy (Note 2)		E _{AS}	244	mJ	
Avalanche current		I _{AR}	2.5	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	3.5	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55 to 150	°C	



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

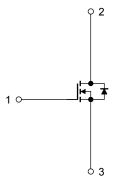
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.57	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1:Ensure that the channel temperature does not exceed 150°C.

Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}(\text{initial})$, L = 69 mH, $R_G = 25 \Omega$, $I_{AR} = 2.5 \text{ A}$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.



Electrical Characteristics (Ta = 25°C)

Char	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I _{GSS}	$V_{GS}=\pm30~V,~V_{DS}=0~V$	_	_	±1	μА
Drain cut-off curr	ent	I _{DSS}	V _{DS} = 650 V, V _{GS} = 0 V	_	_	10	μА
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	650	_	_	V
Gate threshold ve	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.4	_	4.4	V
Drain-source ON	-resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 1.3 A	_	2.3	2.51	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 1.3 A	0.6	2.2	_	S
Input capacitance		C _{iss}		_	490	_	pF
Reverse transfer capacitance		C _{rss}	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	3	_	
Output capacitance		C _{oss}			55	_	
Switching time	Rise time	t _r	$\begin{array}{c c} 10 \text{ V} \\ \text{VGS} \\ 0 \text{ V} \\ \hline \\ 50 \Omega \end{array} \begin{array}{c} \text{I}_D = 1.3 \text{A} \\ \text{VOUT} \\ \text{V}_{DD} \approx 200 \text{ V} \\ \text{Duty} \leq 1\%, \ t_W = 10 \mu\text{s} \end{array}$	_	18	_	
	Turn-on time	t _{on}			40	_	
	Fall time	t _f		_	8	_	ns
	Turn-off time	t _{off}		_	55	_	
Total gate charge		Qg		_	11	_	
Gate-source charge		Q _{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$	_	6	_	nC
Gate-drain charge		Q _{gd}		_	5	_	

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	2.5	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	10	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 2.5 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 2.5 A, V _{GS} = 0 V,	_	1000	_	ns
Reverse recovery charge	Q _{rr}	dl _{DR} /dt = 100 A/μs	_	5	_	μС

Marking

